

MOSFET – Power, Single, N-Channel, μ8FL

30 V, 4.2 mΩ, 71 A

NVTFS4C06N

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- NVTFS4C06NWF Wettable Flanks Product
- NVT Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V_{DSS}	30	V
Gate-to-Source Voltage			V_{GS}	±20	V
Continuous Drain Current	Steady	$T_A = 25^{\circ}C$	I _D	21	Α
R _{θJA} (Notes 1, 2, 4)	State	T _A = 100°C		15	
Power Dissipation R _{θJA}		$T_A = 25^{\circ}C$	P_{D}	3.1	W
(Note 1, 2, 4)		T _A = 100°C		1.6	
Continuous Drain Current		$T_A = 25^{\circ}C$	I _D	71	
R _{θJC} (Note 1, 3, 4)		$T_A = 100^{\circ}C$		50	Α
Power Dissipation		$T_A = 25^{\circ}C$	P_{D}	37	W
R _{θJC} (Note 1, 3, 4)		$T_A = 100^{\circ}C$		18	
Pulsed Drain Current	$T_A = 25^{\circ}C$	C, t _p = 10 μs	I_{DM}	367	Α
Operating Junction and Sto	rage Temp	erature	T _J ,	-55 to +175	°C
Course Current (Bady Died	۵)		T _{stg}		Λ
Source Current (Body Diode)			I _S	33	Α
Single Pulse Drain-to-Source Avalanche Energy (T _J = 25°C, I _L = 26 A _{pk} , L = 0.1 mH)			E _{AS}	34	mJ
Lead Temperature for Solde (1/8" from Case for 10 s)	ering Purpo	ses	TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

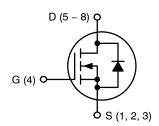
THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State (Drain) (Notes 1 and 4)	$R_{\theta JC}$	4.1	°C/W
Junction-to-Ambient - Steady State (Notes 1 and 2)	$R_{\theta JA}$	48	

- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm² 2 oz. Cu pad.
- Assumes heat-sink sufficiently large to maintain constant case temperature independent of device power.
- Continuous DC current rating. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.

V _{(BR)DSS}	R _{DS(on)} MAX	I _D MAX
30 V	4.2 mΩ @ 10 V	71 A
	6.1 mΩ @ 4.5 V	

N-Channel



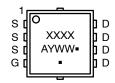


WDFN8 3.3x3.3, 0.65P CASE 511AB



WDFNW8 3.3x3.3, 0.65P (Full-Cut μ8FL WF) CASE 515AN

MARKING DIAGRAM



4C06 = Specific Device Code for

NVMTS4C06N

06WF = Specific Device Code of

NVTFS4C06NWF

A = Assembly Location

Y = Year WW = Work Week

= Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

See detailed ordering, marking and shipping information on page 5 of this data sheet.

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

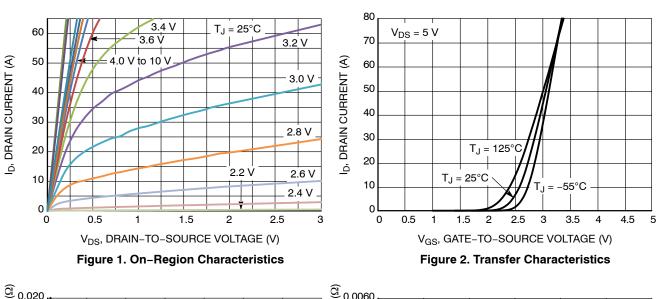
Parameter	Symbol	Test Condi	tion	Min	Тур	Max	Unit
OFF CHARACTERISTICS		•					
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu$	ıA	30	-	_	V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /			=	14.4	-	mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V,	$T_J = 25^{\circ}C$	-	-	1.0	μΑ
		V _{DS} = 24 V	T _J = 125°C	-	-	10	
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20$	V	-	-	±100	nA
ON CHARACTERISTICS (Note 5)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_{D} = 250$	μΑ	1.3	_	2.2	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J			-	3.8	-	mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 30 A	-	3.4	4.2	mΩ
		V _{GS} = 4.5 V	I _D = 30 A	-	4.9	6.1	
Forward Transconductance	9FS	V _{DS} = 1.5 V, I _D = 15 A	Ā	-	58	-	S
Gate Resistance	R_{G}	T _A = 25°C		-	1.0	-	Ω
CHARGES AND CAPACITANCES							
Input Capacitance	C _{ISS}	V _{GS} = 0 V, f = 1 MHz	, V _{DS} = 15 V	-	1683	-	pF
Output Capacitance	C _{OSS}			-	841	-	
Reverse Transfer Capacitance	C _{RSS}			-	40	-	
Capacitance Ratio	C _{RSS} /C _{ISS}	V _{GS} = 0 V, V _{DS} = 15 V, f = 1 MHz		_	0.023	-	
Total Gate Charge	Q _{G(TOT)}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}; I_D = 30 \text{ A}$		-	11.6	-	nC
Threshold Gate Charge	Q _{G(TH)}			-	2.6	-	
Gate-to-Source Charge	Q _{GS}			-	4.7	-	1
Gate-to-Drain Charge	Q_{GD}			-	4.0	-	
Gate Plateau Voltage	V _{GP}			-	3.1	_	V
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 10 V, V _{DS} = 15	5 V; I _D = 30 A	-	26	_	nC
SWITCHING CHARACTERISTICS (Note 6)	, ,						
Turn-On Delay Time	t _{d(ON)}	V _{GS} = 4.5 V, V _{DS} = 1	5 V,	-	10	-	ns
Rise Time	t _r	$I_D = 15 \text{ A}, R_G = 3.0 \Omega$	2	-	32	-	
Turn-Off Delay Time	t _{d(OFF)}			-	18	-	1
Fall Time	t _f			-	5.0	-	
Turn-On Delay Time	t _{d(ON)}	V _{GS} = 10 V, V _{DS} = 15	5 V,	-	8.0	-	ns
Rise Time	t _r	$I_D = 15 \text{ A}, R_G = 3.0 \Omega$	2	-	28	_	
Turn-Off Delay Time	t _{d(OFF)}			-	24	_	
Fall Time	t _f			-	3.0	_	
DRAIN-SOURCE DIODE CHARACTERISTIC							
Forward Diode Voltage	V_{SD}	V _{GS} = 0 V,	T _J = 25°C	_	0.8	1.1	V
		I _S = 10 A	T _J = 125°C	_	0.63	_	
Reverse Recovery Time	t _{RR}	V _{GS} = 0 V, dIS/dt = 1		-	34	_	ns
Charge Time	ta	I _S = 30 A		_	17	-	
Discharge Time	t _b			-	17	_	
Reverse Recovery Charge	Q _{RR}	i		_	22	_	nC

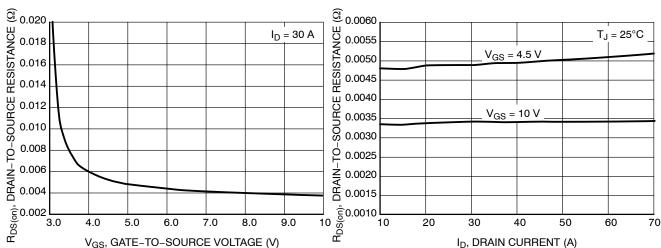
Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

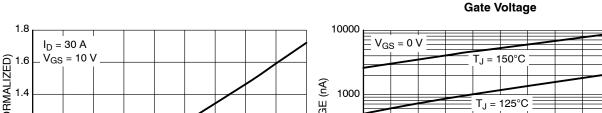
5. Pulse Test: pulse width $\leq 300~\mu s$, duty cycle $\leq 2\%$.

^{6.} Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS







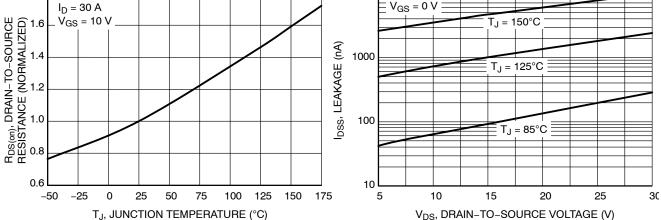


Figure 5. On-Resistance Variation with **Temperature**

Figure 3. On-Resistance vs. V_{GS}

Figure 6. Drain-to-Source Leakage Current vs. Voltage

Figure 4. On-Resistance vs. Drain Current and

TYPICAL CHARACTERISTICS

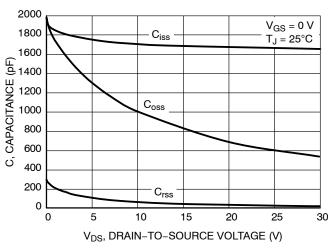


Figure 7. Capacitance Variation

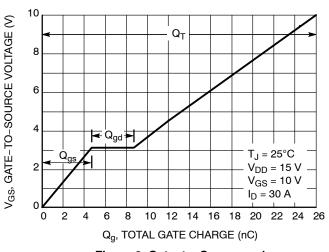


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

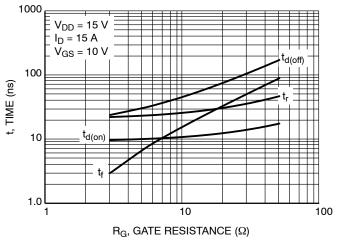


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

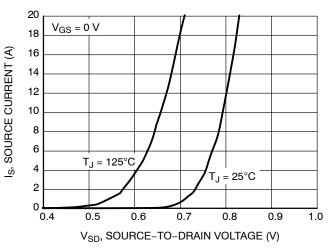


Figure 10. Diode Forward Voltage vs. Current

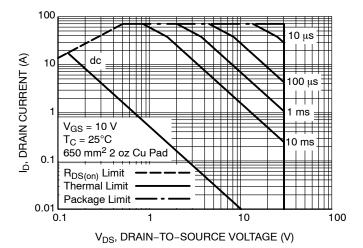


Figure 11. Maximum Rated Forward Biased Safe Operating Area

TYPICAL CHARACTERISTICS

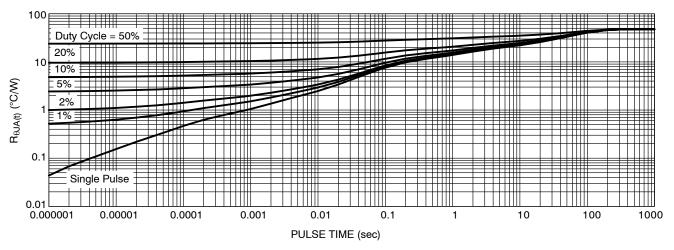


Figure 12. Thermal Response

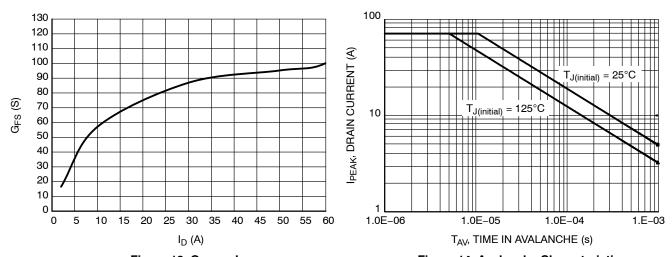


Figure 13. G_{FS} vs. I_D

Figure 14. Avalanche Characteristics

ORDERING INFORMATION

Device	Package	Shipping [†]
NVTFS4C06NTAG	WDFN8 3.3x3.3, 0.65P (Pb-Free)	1500 / Tape & Reel
NVTFS4C06NWFTAG	WDFNW8 3.3x3.3, 0.65P (Full-Cut μ8FL WF) (Pb-Free)	1500 / Tape & Reel
NVTFS4C06NTWG	WDFN8 3.3x3.3, 0.65P (Pb-Free)	5000 / Tape & Reel
NVTFS4C06NWFTWG	WDFNW8 3.3x3.3, 0.65P (Full-Cut μ8FL WF) (Pb-Free)	5000 / Tape & Reel

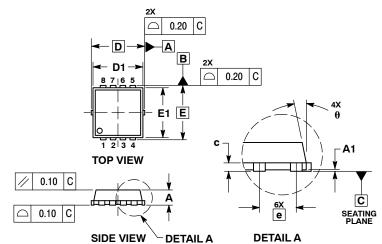
[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.





WDFN8 3.3x3.3, 0.65P CASE 511AB ISSUE D

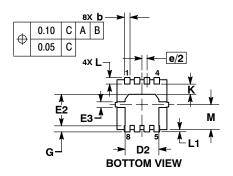
DATE 23 APR 2012



NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
 CONTROLLING DIMENSION: MILLIMETERS.
 DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH
 PROTRUSIONS OR GATE BURRS.

	MI	LLIMETE	RS		INCHES	
DIM	MIN	NOM	MAX	MIN	NOM	MAX
Α	0.70	0.75	0.80	0.028	0.030	0.031
A1	0.00		0.05	0.000		0.002
b	0.23	0.30	0.40	0.009	0.012	0.016
С	0.15	0.20	0.25	0.006	0.008	0.010
D		3.30 BSC		C	.130 BSC)
D1	2.95	3.05	3.15	0.116	0.120	0.124
D2	1.98	2.11	2.24	0.078	0.083	0.088
Е		3.30 BSC		C	.130 BSC)
E1	2.95	3.05	3.15	0.116	0.120	0.124
E2	1.47	1.60	1.73	0.058	0.063	0.068
E3	0.23	0.30	0.40	0.009	0.012	0.016
е		0.65 BSC	;	Ú	0.026 BS	2
G	0.30	0.41	0.51	0.012	0.016	0.020
K	0.65	0.80	0.95	0.026	0.032	0.037
L	0.30	0.43	0.56	0.012	0.017	0.022
L1	0.06	0.13	0.20	0.002	0.005	0.008
M	1.40	1.50	1.60	0.055	0.059	0.063
θ	0 °		12 °	0 °		12 °

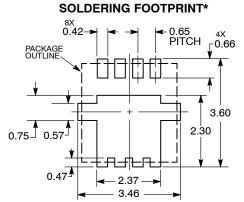


GENERIC MARKING DIAGRAM*



XXXXX = Specific Device Code Α = Assembly Location

= Year WW = Work Week = Pb-Free Package



DIMENSION: MILLIMETERS

*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

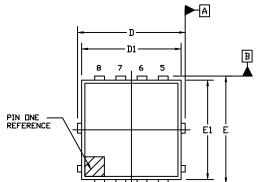
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DESCRIPTION:	WDFN8 3.3X3.3, 0.65P		PAGE 1 OF 1

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^{*}This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "■", may or may not be present. Some products may not follow the Generic Marking.

WDFNW8 3.3x3.3, 0.65P (Full-Cut μ8FL WF) CASE 515AN ISSUE O

DATE 25 AUG 2020



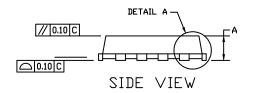
TOP VIEW

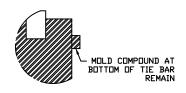


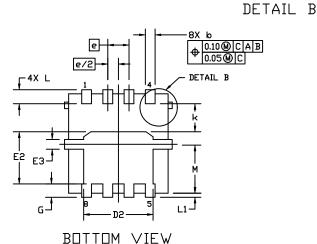
- 1. DIMENSIONING AND TOLERANCING PER.ASME Y14.5M, 2009.
- 2. CONTROLLING DIMENSION: MILLIMETERS
- DIMENSION D1 AND E1 D0 NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.

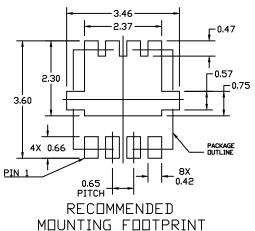
	PLATED AREA -c -
DETAIL A	C SEATING

	MILLIMETERS				
DIM	MIN.	NDM.	MAX.		
Α	0.70	0.75	0.80		
A1	0.00		0.05		
b	0.23	0.30	0.40		
С	0.15	0.20	0.25		
D	3.05	3.30	3.55		
D1	2.95	3.05	3.15		
D2	1.98	2.11	2.24		
Ε	3.05	3.30	3.55		
E1	2.95	3.05	3.15		
E2	1.47	1.60	1.73		
E3	0.23	0.30	0.40		
e		0.65 BSC			
G	0.30	0.41	0.51		
K	0.65	0.80	0.95		
L	0.30	0.43	0.59		
L1	0.06	0.13	0.20		
М	1.40	1.50	1.60		









* For additional information on our Pb-Free strategy and soldering details, please download the IIN Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

GENERIC MARKING DIAGRAM*

XXXX AYWW• XXXX = Specific Device Code

A = Assembly Location

Y = Year

WW = Work Week

= Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

(Note: Microdot may be in either location)

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